

UNITED STATES PATENT AND TRADEMARK OFFICE  
**CERTIFICATE OF CORRECTION**

PATENT NO. : 7,255,719 B2  
APPLICATION NO. : 10/523844  
DATED : August 14, 2007  
INVENTOR(S) : Kanno et al.

Page 1 of 1

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

ON THE TITLE PAGE:

The title should read as follows:

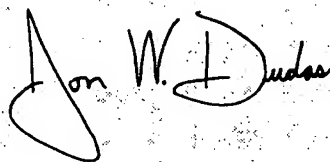
Item (54) WAFER ROTATION DEVICE AND EDGE FLAW INSPECTION  
APPARATUS HAVING THE DEVICE

Inventor Kanno's city should read as follows:

Item (75) Takashi Kanno, Koshigaya-shi (JP)

Signed and Sealed this

Fourth Day of December, 2007

A handwritten signature in black ink, appearing to read "Jon W. Dudas", is written over a faint, circular embossed seal of the United States Patent and Trademark Office.

JON W. DUDAS  
*Director of the United States Patent and Trademark Office*